

Problem 17.1

Regenerate Table 17.1. If the water level where a cup of water is removed is 4.7 instead of 5. How are the results affected? If the sensing time is increased how are the final results affected (compare a water level of 5 against 4.7).

In table 17.1, if the water level to remove a cup of water is 4.7 instead of 5, the results are not affected. This is shown in the table below.

Time (sec)	Water level in sigma buckets(cup)	Remove cup?	Running average
0	4.7	no	0
10	4.95	yes	1
20	4.2	no	0.5
30	4.45	no	0.33
40	4.7	no	0.25
50	4.95	yes	0.4
60	4.2	no	0.33
70	4.45	no	0.29
80	4.7	no	0.25
90	4.95	yes	0.33
100	4.2	no	0.3
110	4.45	no	0.27
120	4.7	no	0.25
130	4.95	yes	0.3
140	4.2	no	0.29
150	4.45	no	0.26
160	4.7	no	0.25
170	4.95	yes	0.29

In the following table, the sensing time increases to 370 sec. The final results compare both water level 5 and 4.7. From the table we can see, the longer we sense the closer our output moves to 0.25 cup/10 seconds. And, if there is any error, it will average out over time.

Water level =4.7 cup:

Water level =5 cup:

Time (sec)	Water level in sigma buckets(cup)	Remove cup?	Running average	Water level in sigma buckets(cup)	remove cup?	Running average
0	4.7	no	0	5	no	0
10	4.95	yes	1	5.25	yes	1
20	4.2	no	0.5	4.5	no	0.5
30	4.45	no	0.33	4.75	no	0.33
40	4.7	no	0.25	5	no	0.25
50	4.95	yes	0.4	5.25	yes	0.4
60	4.2	no	0.33	4.5	no	0.33
70	4.45	no	0.29	4.75	no	0.29
80	4.7	no	0.25	5	no	0.25
90	4.95	yes	0.33	5.25	yes	0.33
100	4.2	no	0.3	4.5	no	0.3
110	4.45	no	0.27	4.75	no	0.27
120	4.7	no	0.25	5	no	0.25
130	4.95	yes	0.3	5.25	yes	0.3
140	4.2	no	0.29	4.5	no	0.29
150	4.45	no	0.26	4.75	no	0.26
160	4.7	no	0.25	5	no	0.25
170	4.95	yes	0.29	5.25	yes	0.29
180	4.2	no	0.28	4.5	no	0.28
190	4.45	no	0.26	4.75	no	0.26
200	4.7	no	0.25	5	no	0.25
210	4.95	yes	0.29	5.25	yes	0.29
220	4.2	no	0.27	4.5	no	0.27
230	4.45	no	0.26	4.75	no	0.26
240	4.7	no	0.25	5	no	0.25
250	4.95	yes	0.28	5.25	yes	0.28
260	4.2	no	0.27	4.5	no	0.27
270	4.45	no	0.26	4.75	no	0.26
280	4.7	no	0.25	5	no	0.25
290	4.95	yes	0.28	5.25	yes	0.28
300	4.2	no	0.27	4.5	no	0.27
310	4.45	no	0.26	4.75	no	0.26
320	4.7	no	0.25	5	no	0.25
330	4.95	yes	0.27	5.25	yes	0.27
340	4.2	no	0.26	4.5	no	0.26
350	4.45	no	0.26	4.75	no	0.26
360	4.7	no	0.25	5	no	0.25
370	4.95	yes	0.27	5.25	yes	0.27

Problem 17.2

time, seconds	water level in the sigma bucket (cups)	add cup? (water level > 5?)	Running average
0	5	no	0
10	4.7	yes	0.5
20	5.4	no	0.33
30	5.1	no	0.25
40	4.8	yes	0.4
50	5.5	no	0.33
60	5.2	no	0.29
70	4.9	yes	0.38
80	5.6	no	0.33
90	5.3	no	0.3
100	5	no	0.27
110	4.7	yes	0.33
120	5.4	no	0.31
130	5.1	no	0.29
140	4.8	yes	0.33
150	5.5	no	0.31
160	5.2	no	0.29
170	4.9	yes	0.33

note: assume 5 cups initially; 0.3 cups leaves every 10 seconds

P17.3

Referring to figure 17.6, with I_{cup} replaced with a resistor R_{cup} , and assuming that the clock frequency is large, (this is required so that ΔV_{bit} is small, which simplifies the equations.) Equations 17.3 through 17.8 are derived below,

$$\text{With, } I_{cup} = I_R = \frac{VDD - V_{bit}}{R_{cup}}$$

$$\frac{I_{bit}}{C_{bit}} = \frac{\Delta V_{bit}}{T} \quad (17.3)$$

$$Q_{bit} = I_{bit} * T = C_{bit} * \Delta V_{bit} \quad (17.4)$$

$$Q_{cup} = \frac{VDD - V_{bit}}{R_{cup}} * \frac{M}{N} * T \quad (17.5)$$

$$Q_{bit} = I_{bit} * T = Q_{cup} = \frac{VDD - V_{bit}}{R_{cup}} * \frac{M}{N} * T \quad (17.6)$$

$$I_{bit} * \frac{R_{cup}}{VDD - V_{bit}} = \frac{M}{N} \quad (17.7)$$

$$\Delta V_{bit,max} = \frac{VDD - V_{bit}}{R_{cup}} * \frac{T}{C_{bit}} \quad (17.8)$$

The current through the resistor must be larger than the I_{bit} . If it is not, the current through the resistor will not be able to keep I_{bit} fed, and V_{bit} will go to zero.

Prob 17-4: Demonstrate, using SPICE simulations, that the error because of parasitics, as seen in fig 17.7, is reduced by connecting the switch to a 1v source instead of ground.

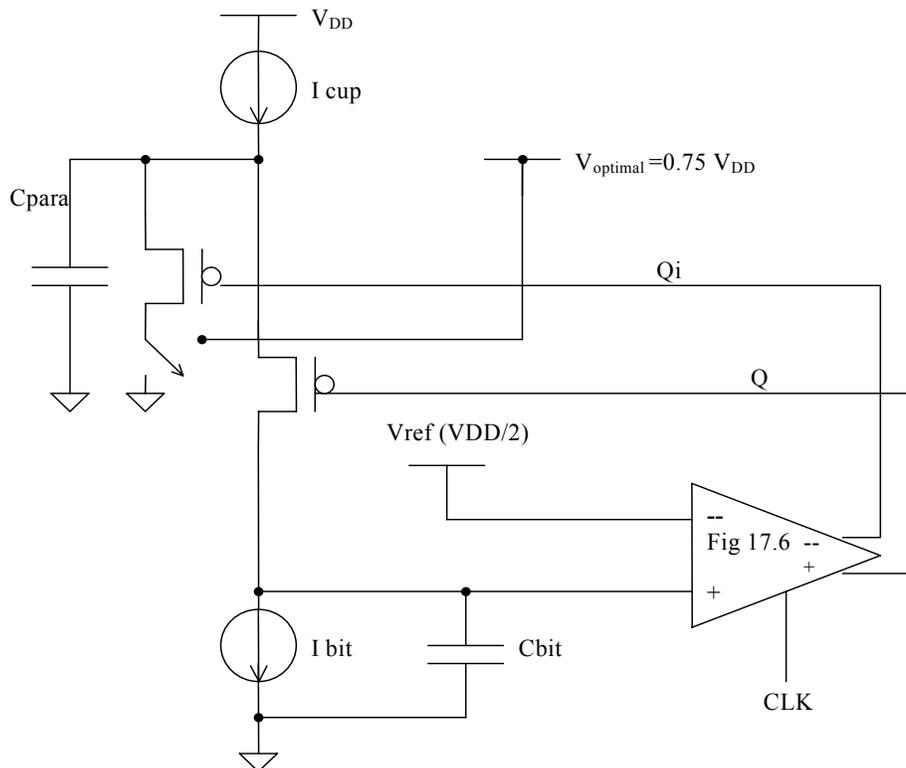
[Ans]:

Based on Fig 17-4-1 and Fig 17-4-2, we can analyze the current source parasitic capacitance effects on DSM sensing precision. SPICE simulation results are shown as Fig 17-4-4, Fig17-4-5, and Fig17-4-6; summarized as Table 17-4-3.

By interpolating the simulation results, we can make the following conclusions:

- (1). Sensing Error because of parasitics, as seen in fig 17.7, is reduced by connecting the switch to a VDD source instead of ground.
- (2). Sensing Error due to $C_{\text{parasitics}}$ can be eliminated by choosing the proper voltage source connected to C_{par} during transition in order to compensate the charge sharing between C_{par} and C_{bit} . As indicated in Fig 17-4-6, I would recommend $0.75V_{\text{DD}}$ instead of V_{DD} .
- (3). Current noise through $C_{\text{parasitics}}$ is also a good indication of charge sharing or injection; we will mainly care about at NO-to-YES transitions.

Fig 17-4-1 Analysis of Current source parasitic Capacitance Effect



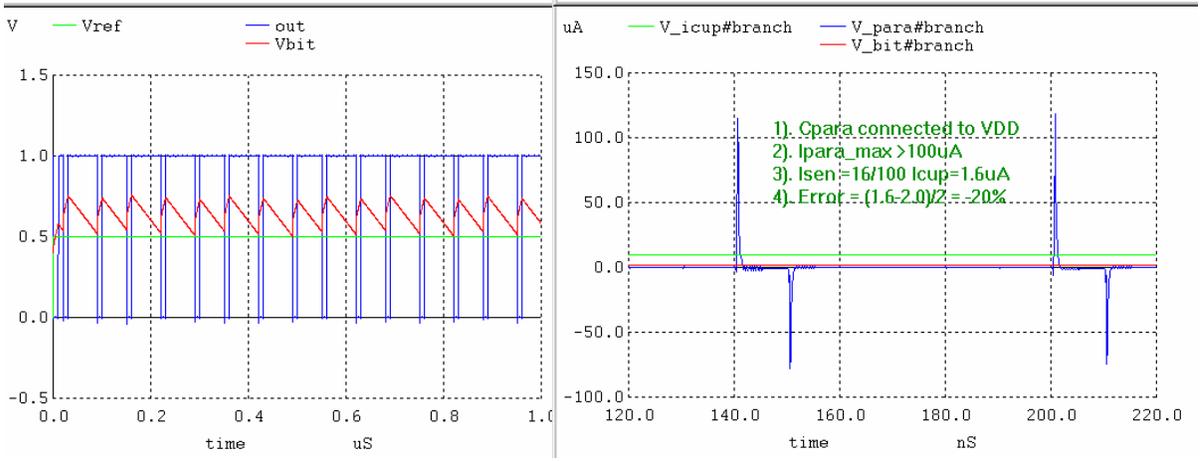
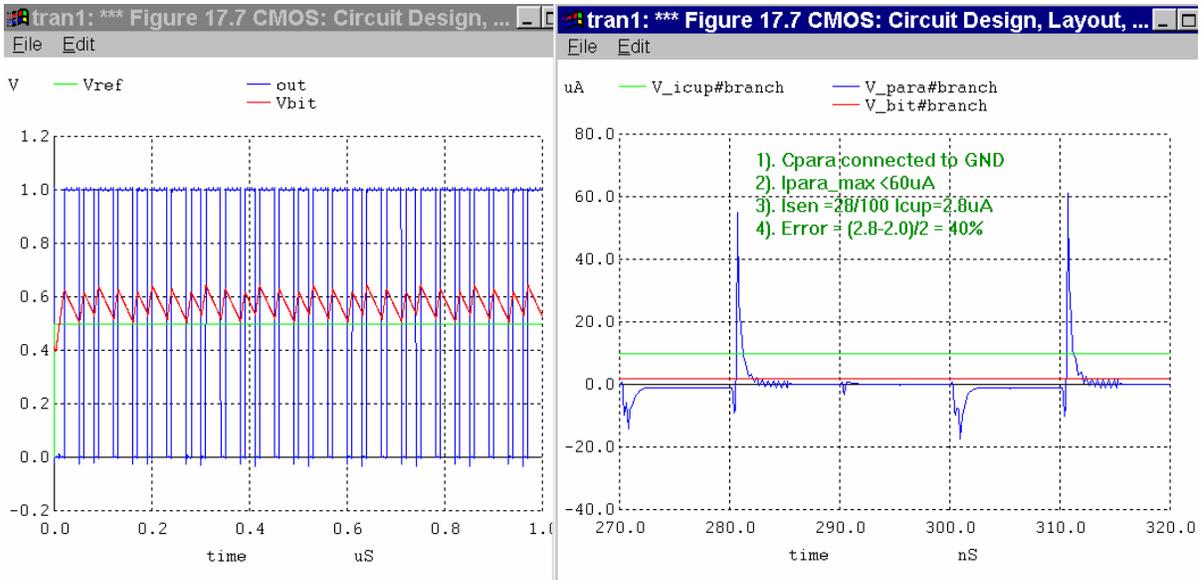


Fig 17-4-5 SPICE Simulation parasitic Capacitance (connect Vref = VDD/2)

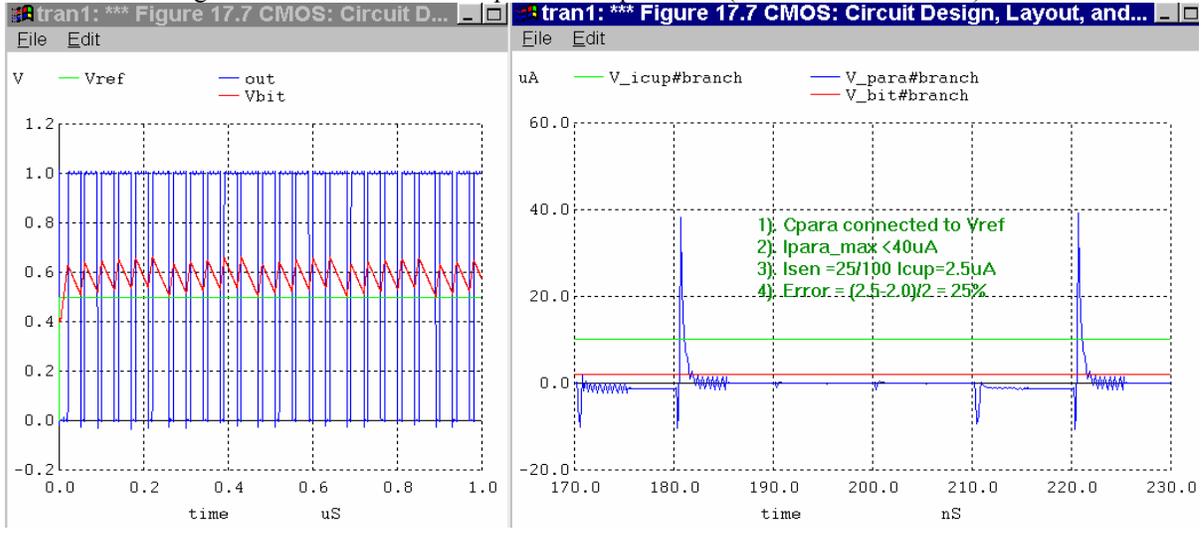
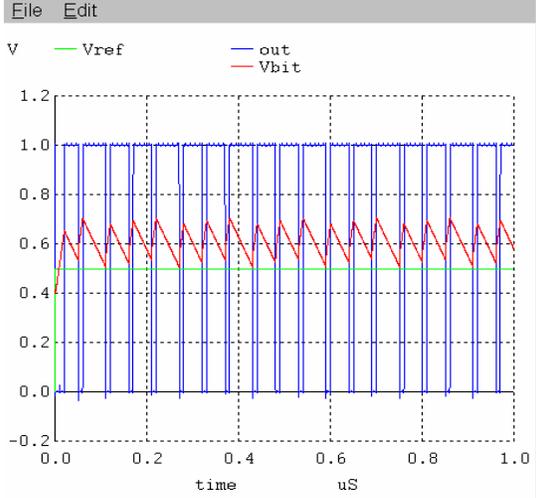
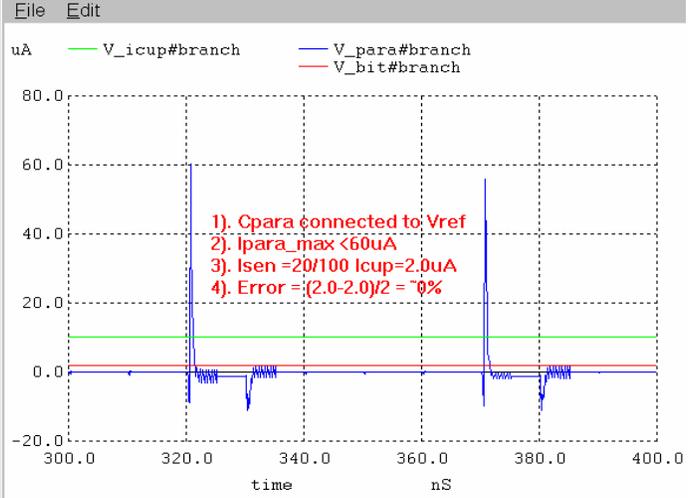


Fig 17-4-6 SPICE Simulation parasitic Capacitance (connect {Vref + VDD}/2 = 0.75VDD) to eliminate sensing error caused by Cpara from current source

tran1: *** Figure 17.7 CMOS: Circuit Des...



tran1: *** Figure 17.7 CMOS: Circuit Design, Layout, a...



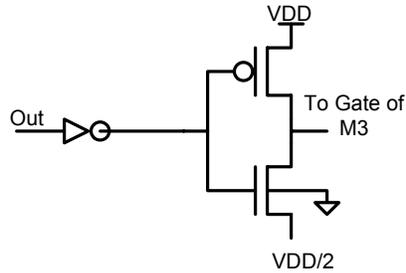
Problem 17.5

Tris Tanadi (ttanadi@hotmail.com)

Showing, using simulations, that if the output of the comparator swings from VDD to VDD/2 we can eliminate M4 in Fig. 17.9 and still have $Q_{cup} = C_{cup} * (VDD - V_{REF} - V_{THP})$. Why? Does the amount of current supply by VDD/2 increase? Could this be a problem?

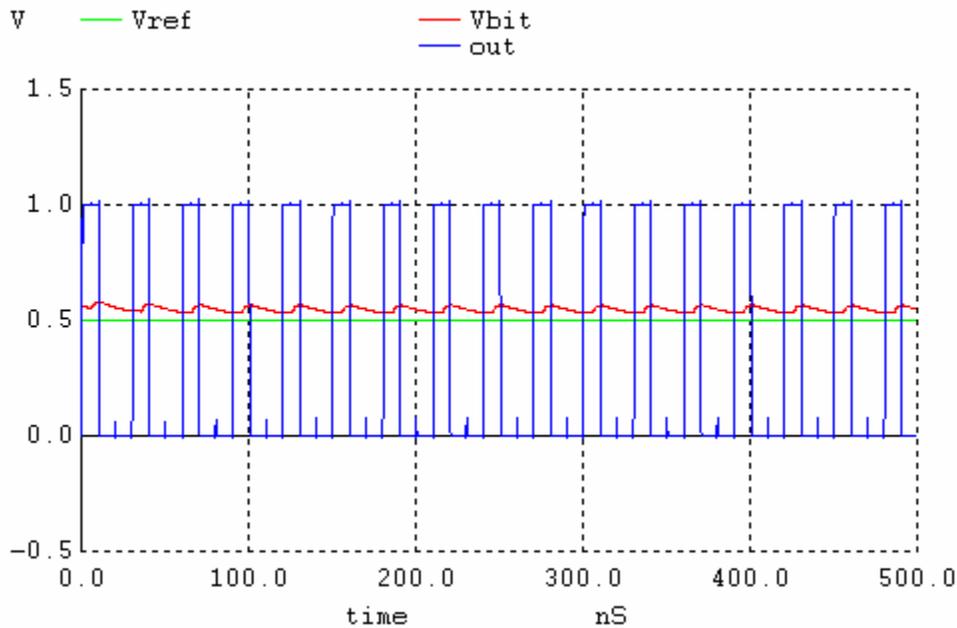
Answer:

We will compare the operation of circuit from Fig. 17.18 with similar circuit but without M4 plus with the following extra circuit.

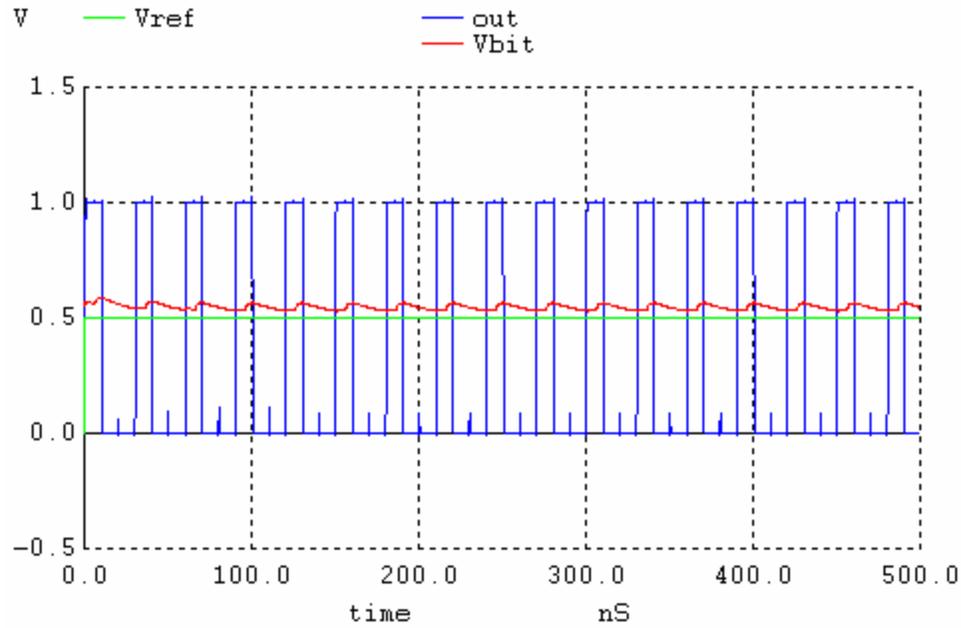


Yes, we will still have $Q_{cup} = C_{cup} * (VDD - V_{REF} - V_{THP})$ because when output of the comparator is low we will dump the charge from C_{cup} to the bit line. Since the logic low of the comparator is VDD/2 which is equal to VREF then the equation still valid. The next two plots are comparing the result using Fig. 17.18 and the new circuit. The Vbit using both circuits are similar. This means that Qcup between two circuits are the same too.

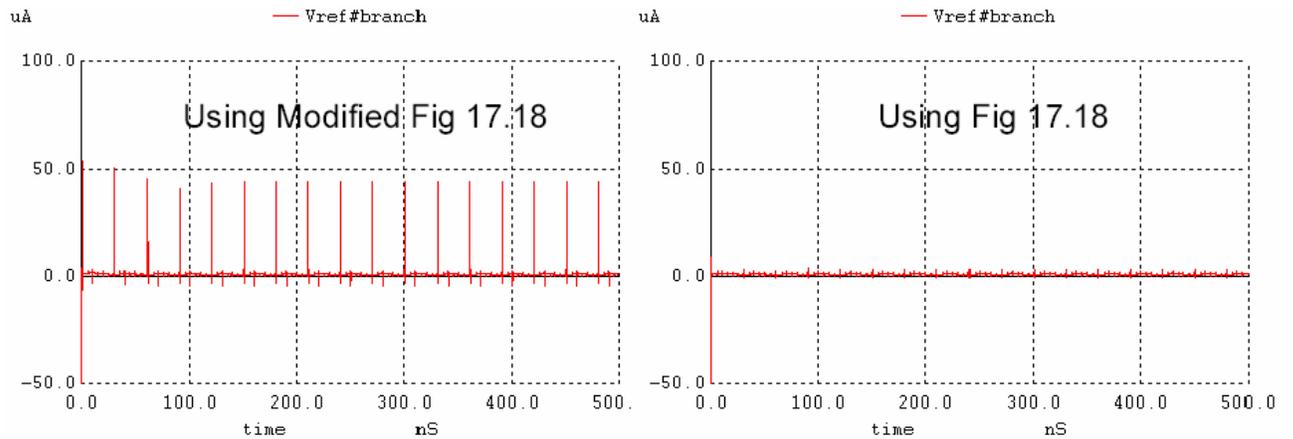
Using Fig 17.18



Using new circuit.



Using the modified Fig 17.19, we will burn more current through VREF because of the extra inverter to change the swing of the comparator output will draw current whenever the output is switched LOW.



The problems of using this circuit are the current increase from VREF and also the extra are required for the extra inverters.

The SPICE source code for the modified circuit:

```
*** Problem 17.5 ***
```

```
.control
destroy all
run
let out=Qi
plot Vbit Vref out
```

```
plot Vref#branch ylimit -10u 100u
.endc
```

```
.option scale=50n
.ic V(vbit)=550m
.tran .25n 500n 0 .25n UIC
```

```
VDD      VDD      0      DC      1
Vphi1    phi1    0      DC      0      PULSE 1 0 1n 0 0 4n 10n
Vphi2    phi2    0      DC      0      PULSE 1 0 6n 0 0 4n 10n
Vclock   clock   0      DC      0      PULSE 0 1 0 0 0 5n 10n
Vref     Vref     0      DC      0.5
```

```
M1      Vd1      phi1    VDD     VDD     PMOS L=1 W=20
M2      Vd2      phi2    Vd1     VDD     PMOS L=1 W=20
M3      Vbit     vx      Vd2     VDD     PMOS L=1 W=20
Ccup    Vd1      0      100f
```

```
Cbit     Vbit     0      500f
Rmbit    Vbit     Vref    50k
```

* The extra circuit from Fig. 17.18

```
X2 Q      Qbar      VDD Inv
M4      vx      Qbar      Vref    0      NMOS L=1 W=10
M5      vx      Qbar      VDD     VDD     PMOS L=1 W=20
```

```
X1      VDD      Vbit     Vref    clock   Qi      Q      Comp
```

```
.subckt Comp      VDD      Inp      Inm      clock   Qi      Q
M1      d1      Outp     db1      0      NMOS L=1 W=10
M2      d2      Outm     db2      0      NMOS L=1 W=10
M3      Outm   Outp     VDD     VDD     PMOS L=1 W=20
M4      Outp   Outm     VDD     VDD     PMOS L=1 W=20
```

```
MS1     Outm   clock   d1      0      NMOS L=1 W=10
MS2     Outp   clock   d2      0      NMOS L=1 W=10
MS3     Outm   clock   VDD     VDD     PMOS L=1 W=20
MS4     Outp   clock   VDD     VDD     PMOS L=1 W=20
```

```
MB1     db1    Inp      0      0      NMOS L=1 W=10
MB2     db2    Inm      0      0      NMOS L=1 W=13
```

```
X1      Outp   Q      Qi      VDD     Nand
X2      Qi    Outm   Q      VDD     Nand
```

```
.ends
```

```
.subckt Nand A B ANANDB VDD
```

```
M1      ANANDB A      d2      0      NMOS L=1 W=10
M2      d2      B      0      0      NMOS L=1 W=10
M3      ANANDB A      VDD     VDD     PMOS L=1 W=20
M4      ANANDB B      VDD     VDD     PMOS L=1 W=20
```

```
.ends
```

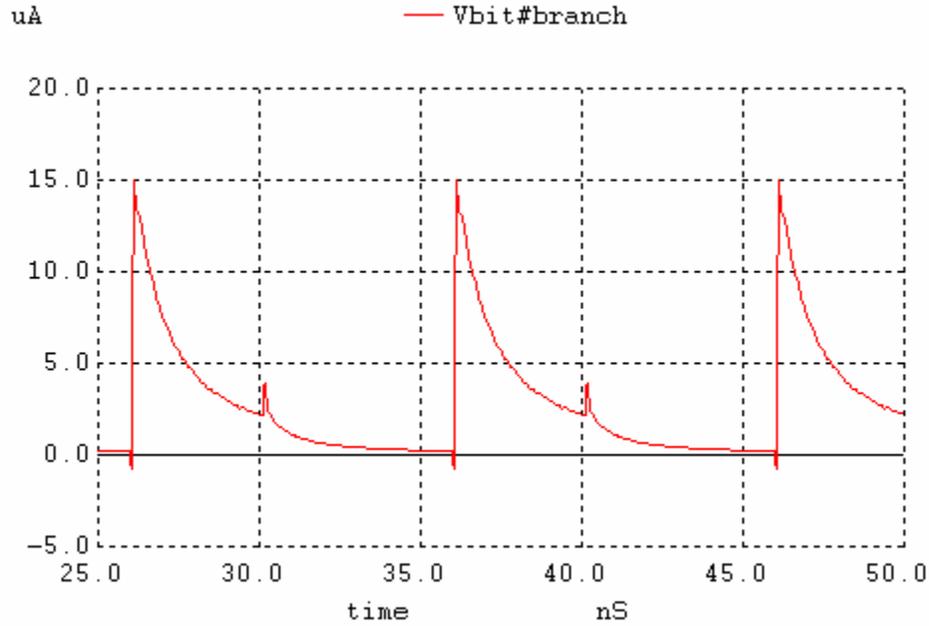
```
.subckt Inv In Out VDD
```

```
M1      out    In      0      0      NMOS L=1 W=10
M2      out    In      VDD     VDD     PMOS L=1 W=20
```

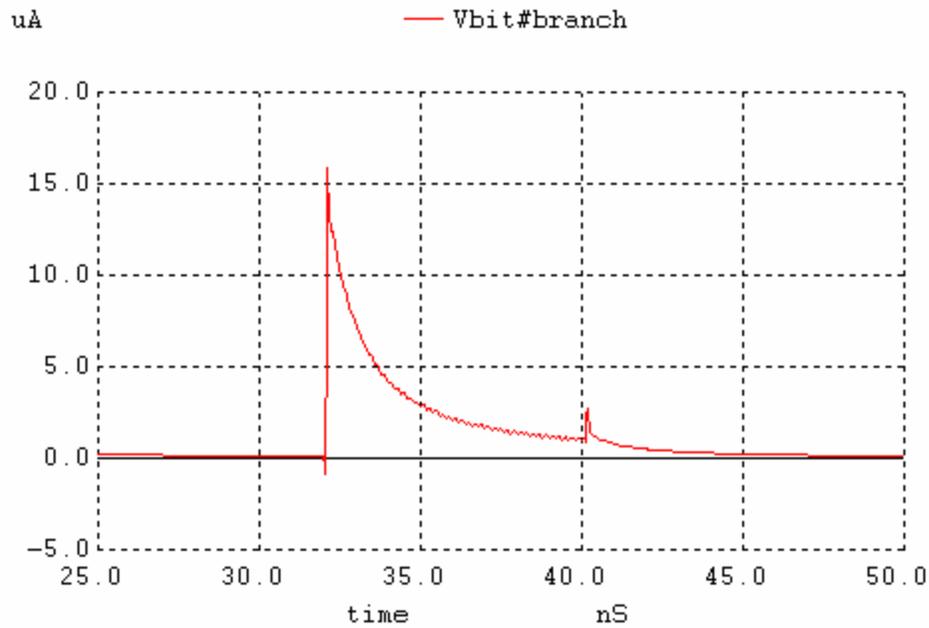
```
.ends
```

17.6 By reducing the clock frequency, C_{cup} will be discharged more so the incomplete settling will be more complete. From the simulation results below, when ϕ_2 shut off, C_{cup} has dumped more charge onto the bit line at lower clock frequency and a wider M4.

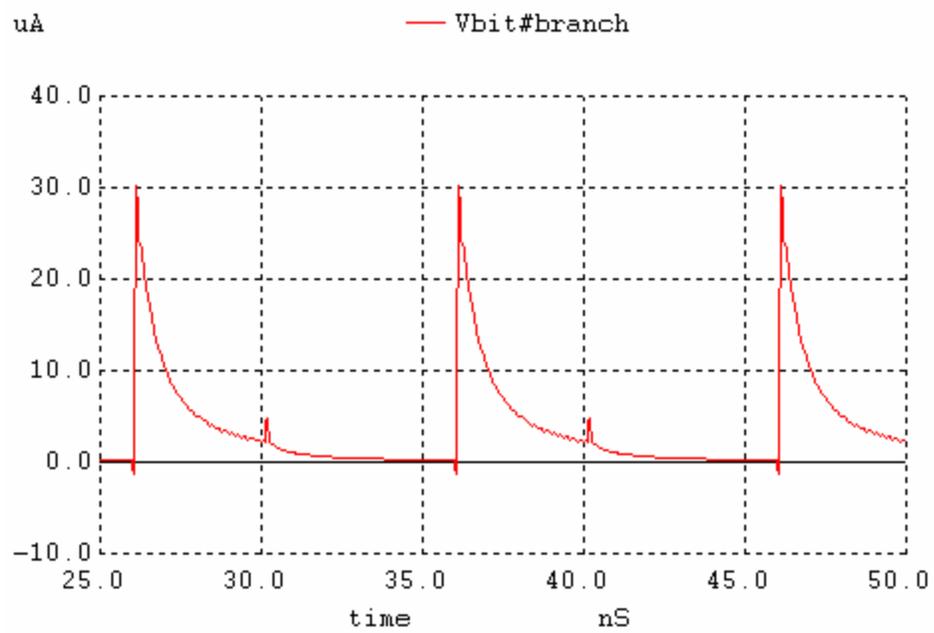
Clock is at 10ns, ϕ_2 low time is at 4 ns and M4 is 40 wide:



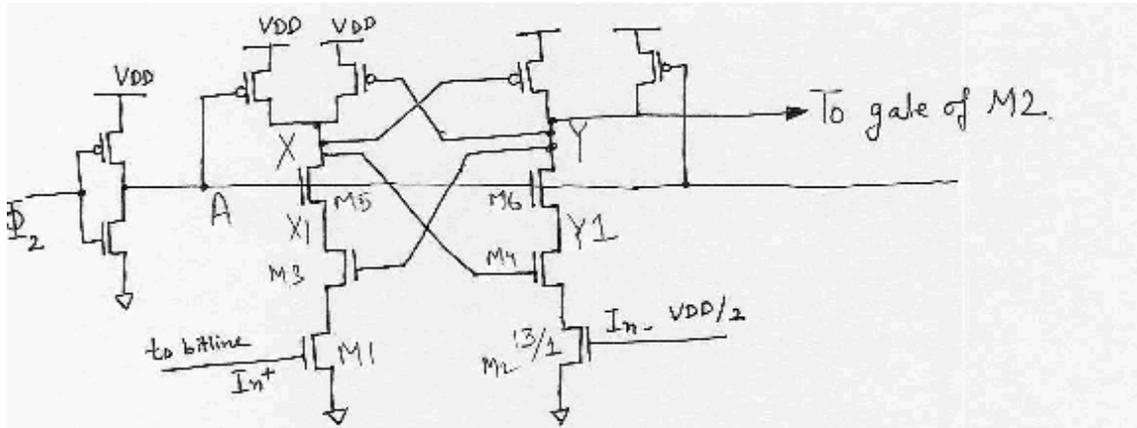
Clock is at 10ns, ϕ_2 low time is at 4 ns:



M4 with width 100.



Problem 17.7



This comparator has built in offset, when bit line Voltage $> \left(\frac{V_{DD}}{2} + V_{os}\right)$, only then it will trip.

$$I_1 = \frac{\beta_1}{2} (V_{GS1} - V_T)^2, \quad I_2 = \frac{\beta_2}{2} (V_{GS2} - V_T)^2$$

$$\frac{K \times 13}{2} \left(\frac{V_{DD}}{2} - V_T\right)^2 = \frac{K \times 10}{2} (V_{GS2} - V_T)^2$$

$$\sqrt{\frac{13}{10}} \left(\frac{V_{DD}}{2} - V_T\right) = (V_{GS2} - V_T)$$

$$1.14 \times \frac{V_{DD}}{2} - 1.14 V_T + V_T = V_{GS2}$$

$$(1.14 - 1) \frac{V_{DD}}{2} - 0.14 V_T = \frac{V_{DD}}{2} + V_{os}$$

$$V_{os} = 0.14 \left(\frac{V_{DD}}{2} - V_T\right)$$

When $\Phi_2 = 1$, $A = 0$, Node X & Y = 1, o/p is 1

Node X1 and Y1 = 0, since gate of M3 are VDD and M5 & M6 are off.

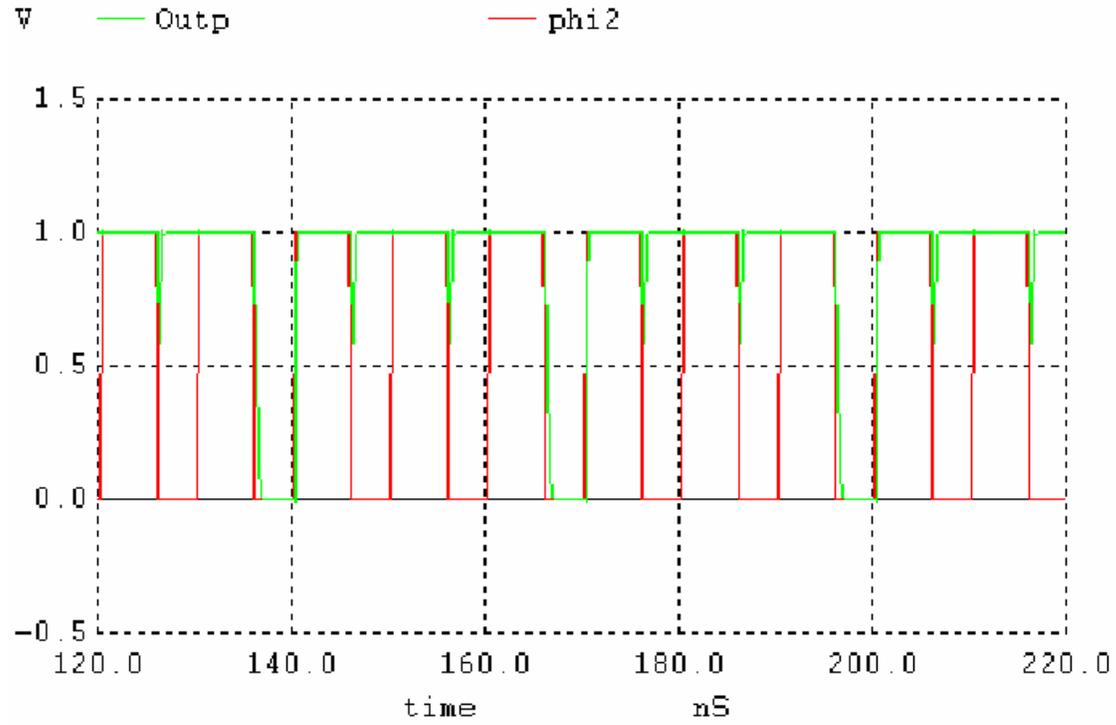
Operation :

When $\phi_2 = 1$, Two upper PMOS transistor will be ON and M5 and M6 will be off, NMOS M3 and M4 has gate at VDD and M1 and M2 has gate at Bit line and VDD/2. Since there is no current in this case because M5 and M6 are off so X1 and Y1 are pulled to gnd. Both the outputs will be high in this case.

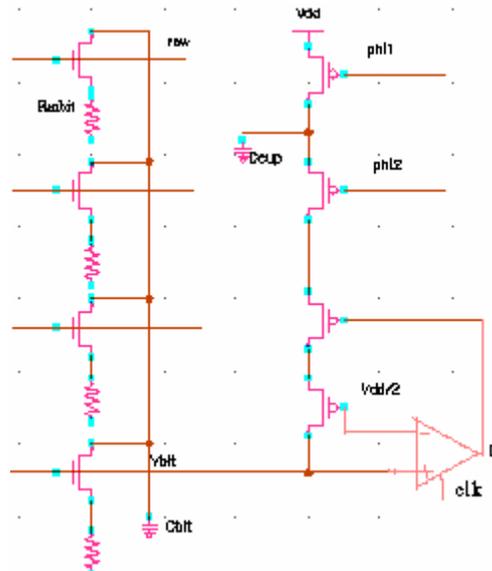
When $\phi_2 = 0$, Sensing operation starts, both outputs are pulled towards low (initially), but at different rates, if bitline $< V_{DD}/2 + V_{os}$ then Output Y will go to gnd finally and X will be at VDD and if bitline $>$

VDD/2 +Vos then output Y will be at VDD but it will glitch (because initially both the outputs are pulled towards gnd).

This glitch may cause Error in Averaging , because when we expect there is no charge transfer from Ccup to Cbit , It can transfer the charge because of the glitch. The simulation below shows the glitch vs. time.



17.8) The following equations and values were chosen for designing DSM circuit that determines the value of resistor that ranges from 100k to 10 MΩ.



First, the value of Ccup was found by using following equation:

$$C_{cup} = \frac{V_{os.T}}{(V_{dd}-V_{thp}) * M/N * R_{bit}}$$

The Vos value picked as a nominal value of 0.05 V, Vthp= 280 mV and f and where Rbit is picked as 50k.

By assuming frequency to be 100MHz, we get Ccup to be 90 fF since the offset varies with process, the capacitor is used as 100fF.

Now Rbit = 25k * N/M

The simulation was done by using Ccup less than Cbit(500fF) and using 100k and 10M for Rbit . The following Rbit was found by using total clock pulses divided by those clock pulses that go high. The simulation results are shown below. By clocking 100 MHz for 4 us, we get 400 clock pulses.

From sim figure 1

$$R_{bit} = 25k \cdot 400/80 = 125k \text{ (the actual value being 100k)}$$

From sim fig 2

$$R_{bit} = 25k \cdot 400/1 = 10M$$

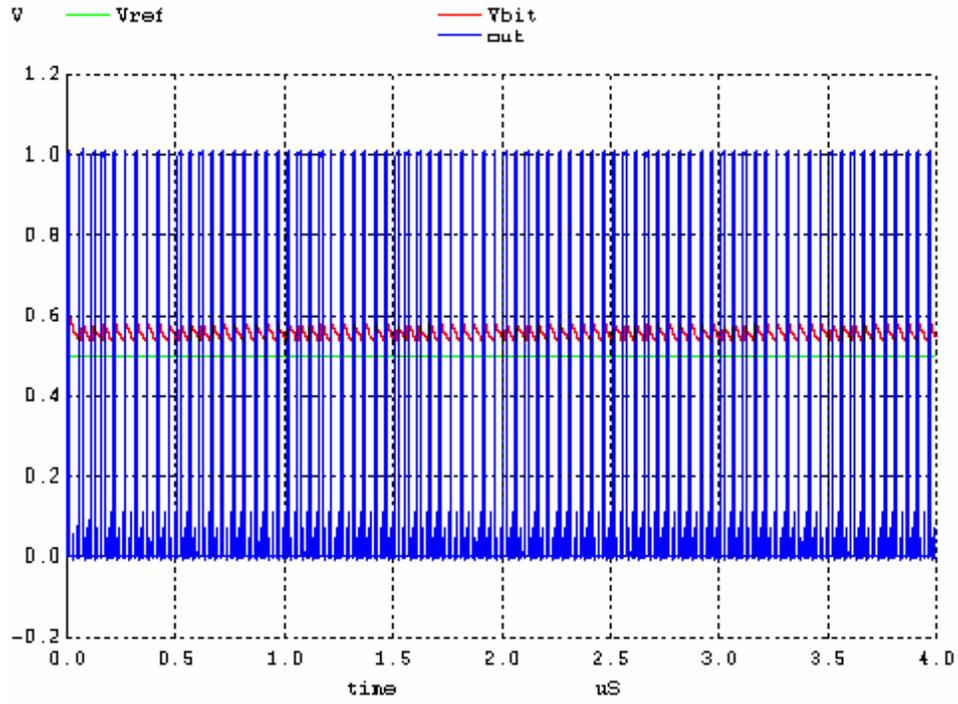


Fig1: For Rmbit = 100K

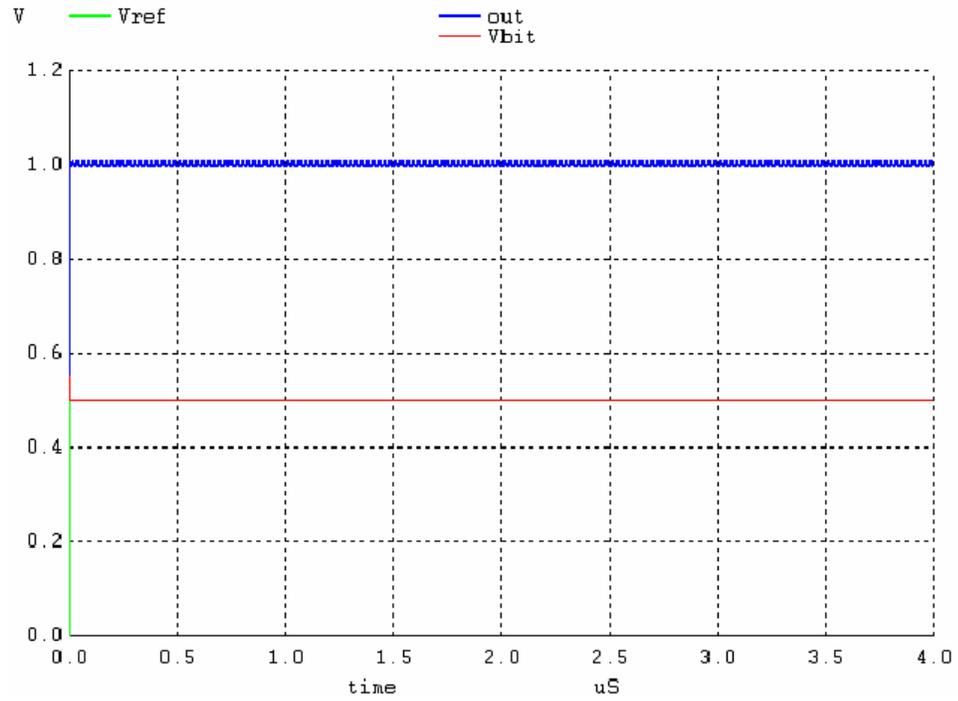


Fig2: For Rmbit= 10M

There will be process variation regarding from the offset voltage and resistance within the MOSFET and threshold voltages that will affect the results. These parameters will affect Ccup since Cbit is always

constant. It will change the clock high pulses (M) thus ultimately giving out the different result. The frequency will also affect the value of C_{cup} thus changing Rmbit.

Problem 17.9

Suppose, that it is desired to have a noise floor of $100\mu V$ RMS in a CMOS imager. Further suppose the sensing circuit doesn't contribute any noise to the sense (the transformation from the analog column voltage to the digital word). Estimate the size of the hold capacitors used to sample both the reference and intensity signals.

Solution: Referring to Equation 8.24 which is the expression for the RMS noise voltage through a capacitor, famously called the “Kay tee over cee” noise:

$$V_{RMS,noise} = \sqrt{\frac{k \cdot T}{C}}$$

where

k = Boltzmann's constant = $1.38 * 10^{-23}$ J/K

T = Temperature in Kelvin = 300 K

C = Capacitance in Farads

$$100\mu V = \sqrt{\frac{1.38 * 10^{-23} \cdot 300}{C}}$$

$$\therefore C = 414 fF$$

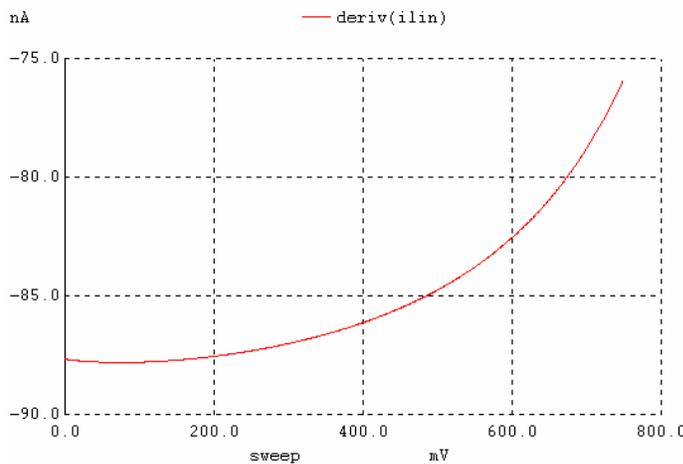
So the size of the hold capacitors that can be allowed for a noise floor of $100\mu V$ in the imager is $414 fF$.

17.10 - Solution by Eric Booth

Using simulations determine if the linearity of the voltage-to-current converter can be made better by adjusting the length of the PMOS device seen in Fig 17.28. Why does, or doesn't, the performance get better?

In order to gather data for this problem, I plotted the derivative of the transfer curve of the device using different L & W values. One way of quantifying the linearity is to divide the change in dI/dV by the ideal value of -100nA/V .

For example, the plot below was created with a device of $L=1$ and $W=5$. The change in dI/dV over the full range is $\sim 12\text{nA/V}$ or 12%. The linearity is best from 0V to 400mV , so it would be useful to quantify this value as well. For this device it is $\sim 2\%$

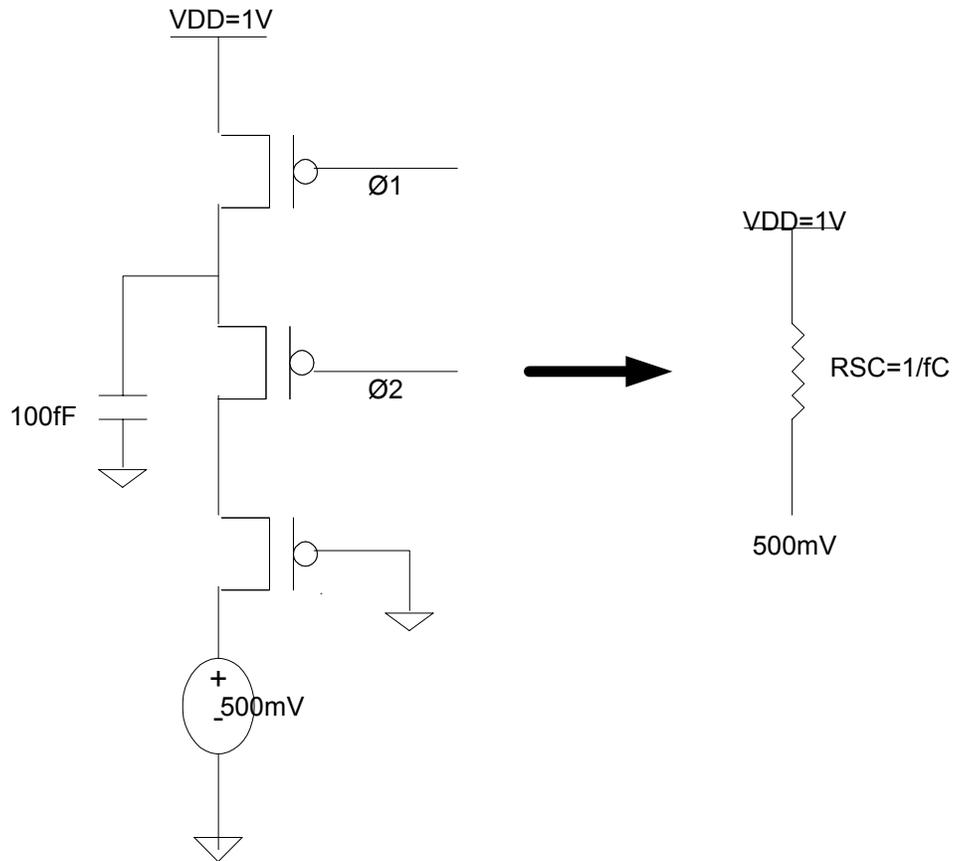


Using this method,

W/L	Linearity (full range)	Linearity (<400mV)
2/1	14%	2%
5/1	12%	2%
10/1	10%	1.5%
20/1	8.5%	1.2%
50/1	7%	1.5%
100/1	6%	3%
20/2	15%	2.5%
20/5	14%	2.5%
20/10	15%	3%
20/20	17%	3%
20/50	20%	4%
20/100	25%	5%

From the table, we can see that as a general rule, increasing W or decreasing L increases the linearity. This is because the linearity of this system requires that the V_{gs} of the device is a constant, however I_d and V_{ds} are changing. A larger β factor ensures that the device will be able to source different currents at different V_{ds} with smaller changes in V_{gs} .

17.11 Solution



The current that flows through the Resistor R_{sc} is

$$I_{avg} = (VDD - 0.5) / R_{sc}$$

Where $R_s = 1/fC$ where $f = 100\text{Mhz}$ and $C = 100\text{fF}$

Therefore $R_{sc} = 100\text{K ohms}$

Therefore $I_{avg} = 0.5 / 100\text{K} = 5\mu\text{ amps}$

*** Problem 17.11 CMOS: Circuit Design, Layout, and Simulation ***

```
.control
destroy all
run
plot phil phi2+1.25 xlimit 100n 150n
plot Vbit#branch xlimit 15n 20n
plot Vbit#branch
print mean(-vdd#branch)
.endc

.option scale=50n

.tran 100p 500n 10n 100p

VDD    VDD    0      DC    1
Vphil  phil   0      DC    0      PULSE 1 0 1n 0 0 4n 10n
```

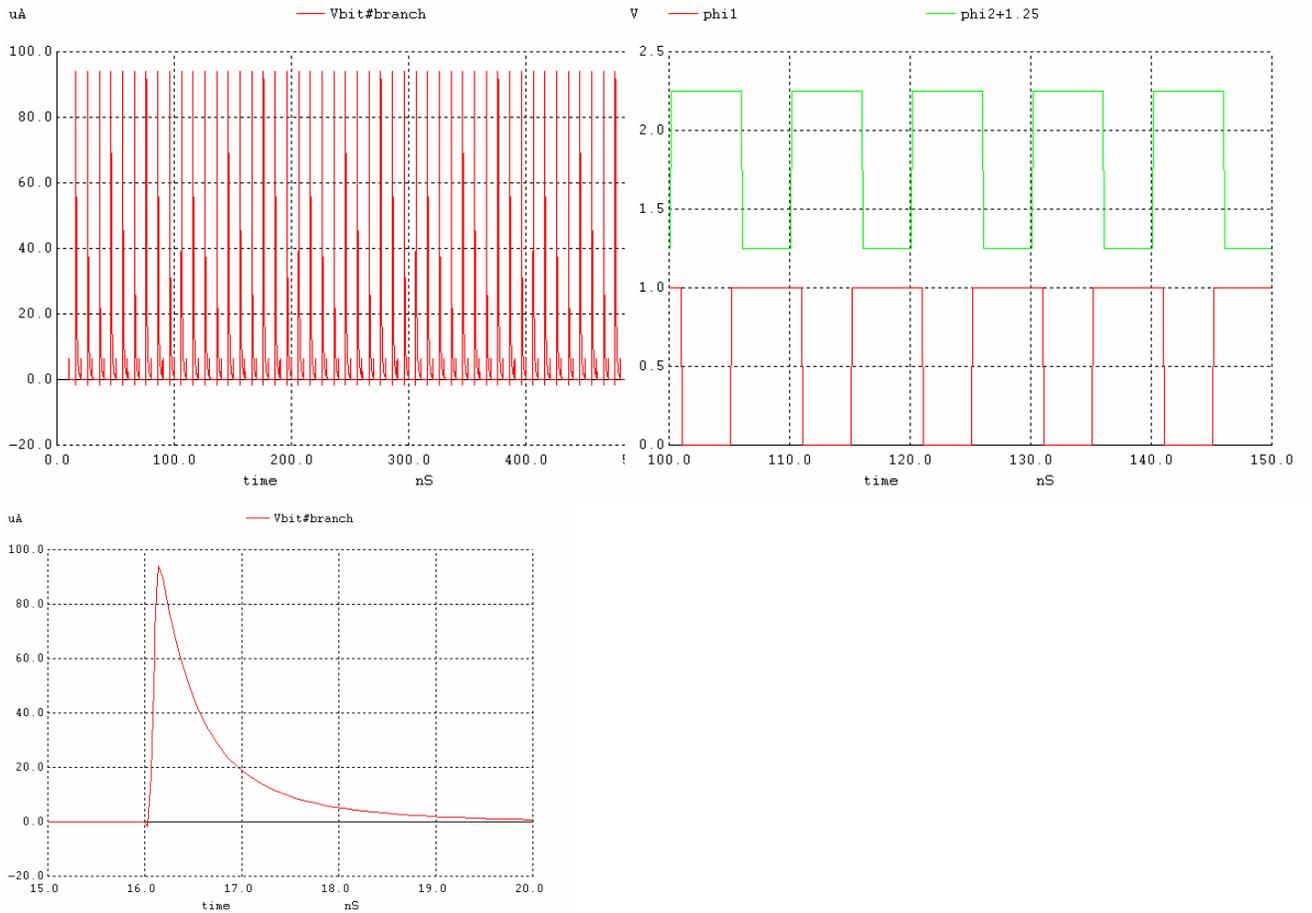
```

Vphi2 phi2 0 DC 0 PULSE 1 0 6n 0 0 4n 10n
*Add resistors to the sim just to make sure the voltage sources always
have a load.
*Rphil phi1 0 1G
*Rphi2 phi2 0 1G
Vbit Vbit 0 DC 0.5

M1 Vd1 phi1 VDD VDD PMOS L=1 W=20
M2 Vd2 phi2 Vd1 vdd PMOS L=1 W=20
M3 Vbit 0 Vd2 Vdd PMOS L=1 W=20
Ccup Vd1 0 100f

```

Simulation Results
 Transient analysis ... 100%
 mean(-vdd#branch) = 9.013932e-06



Problem 17.12

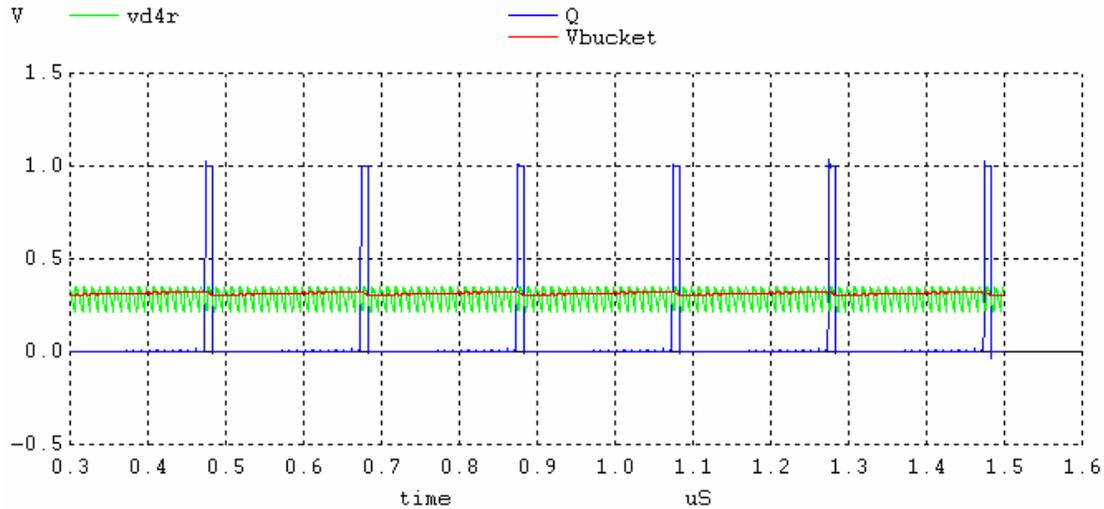
What happens to the simulation results seen in Fig. 17.34, if the time step used in the transient simulation is increased to 1ns? How do the nonoverlapping clocks look with this time step?

Lets focus this solution on the results of Figure 17.34(b).

$$V_R = 650 \text{ mV}$$

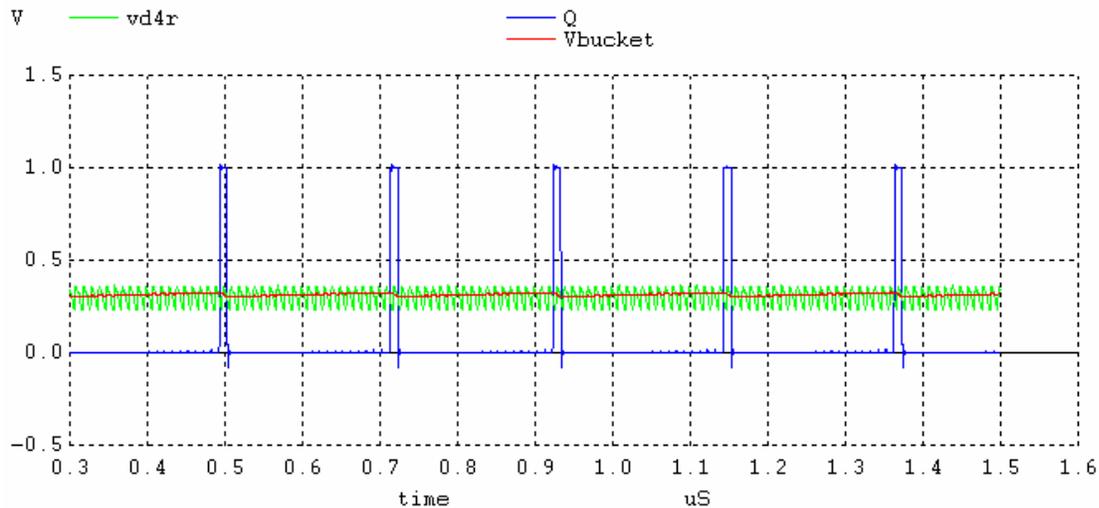
$$V_I = 645 \text{ mV}$$

In Figure 17.34(b) the time step is 0.5ns. This results in the following plot of Q vs time;

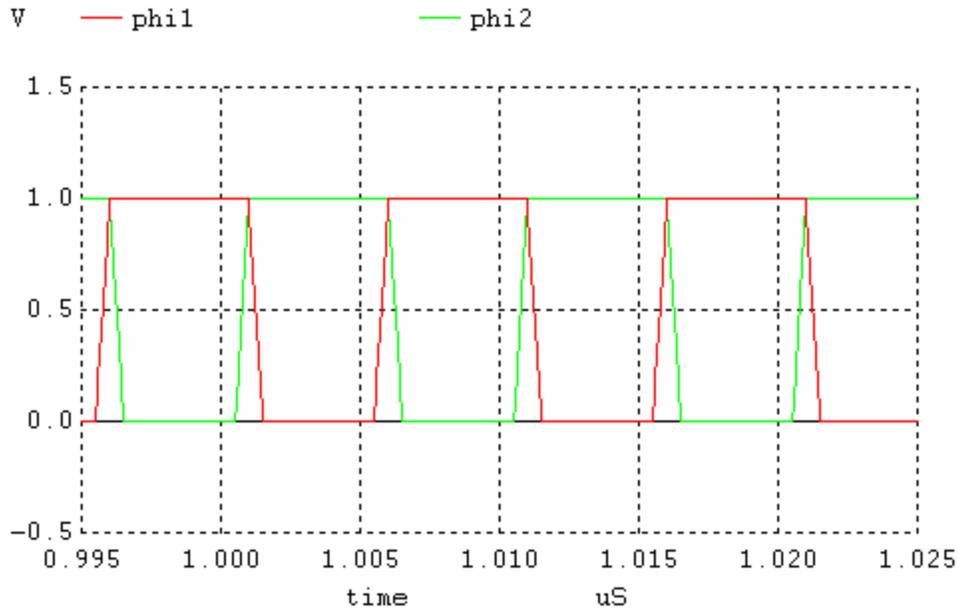


Examining the plot above, we see that Q goes high 5 times while the counter is enabled (0.5us to 1.5us)

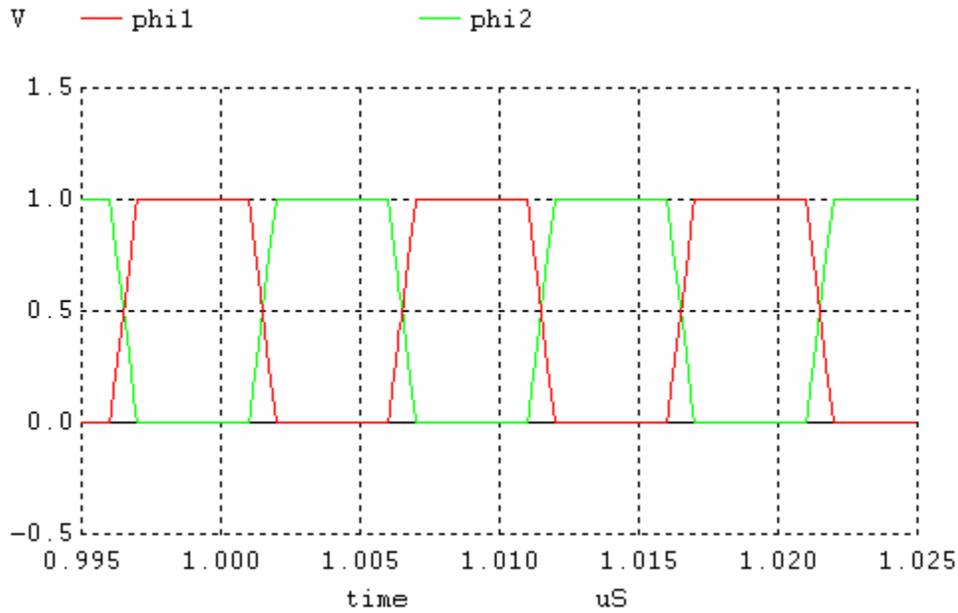
Now if we increase the simulation time step from .5ns to 1ns we get the following plot of Q vs time.



Examining the plot above we see that when the counter is enabled Q goes high 4 times, although when the counter is first enabled, Q is high so depending on the counter the result may be Q high five times. The main point is that Q is going high less frequently. To better understand this, lets take a look at what is happening to the nonoverlapping clocks when the simulation time step is increased (.5ns to 1ns)



time step = 0.5ns



time step = 1ns

The two plots above show a zoomed in view of **phi1** and **phi2**. In both plots the time period is 10ns with the signal high for 4 ns. The difference between the plots is the rise and fall times of the signals. The rise and fall times default to the simulation time step. So in the top plot we have a rise time = fall time = .5ns. Subtracting the total time period(10ns) by the time high(4ns) and the combined rise and fall times(1ns) leaves 5 ns for the signals to be low. In the second plot we have a rise time = fall time = 1ns. This leaves only 4ns for the signal to be low(10ns-4ns-1ns-1ns).

If we look back at Figure 17.33 we see that **phi1** and **phi2** control the switched capacitors via pmos transistors. Since **phi1** and **phi2** are low for a less amount of time with the higher time step, less charge will be able to go to the C_{cup} capacitors. This essentially will increase the R_{SC} for each side, which will lower the current that flows through each side.

With a lower current flowing through both sides it takes longer to drain the charge on C_{bucket} . Yes its true that the charge on C_{cup} is also less but in this case the lower current affects the results more than the smaller C_{cup} charge.

Problem 17.13

Figure 1 shows the outputs of the comparator from figure 17.44. As can be seen, the outputs of the comparator do not make full logic levels. They will reach VDD but not 0.

The glitches seen in Figure, will cause switches to turn on, (when they aren't supposed to,) and inadvertently dump some charge. This will affect the resolution of the sense.

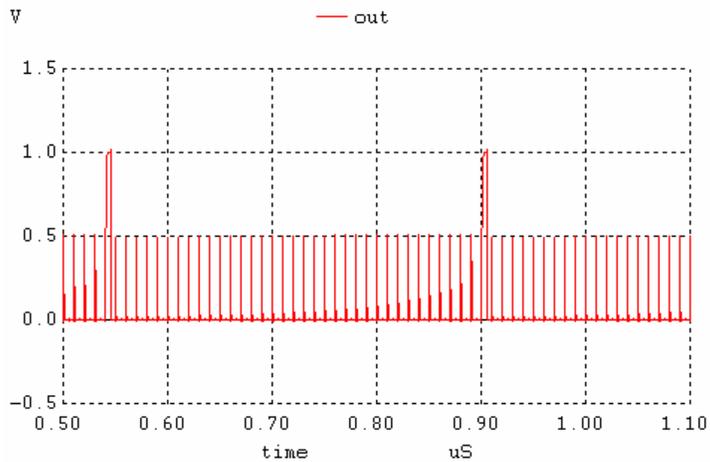


Figure 1.

Adding inverters to the output of the comparator cleans up these glitches (figure 2.). Notice in the netlist, (at the end of this solution,) that the size of the inverter MOSFETS have been adjusted to move the switching point of the inverters to help eliminate the glitches.

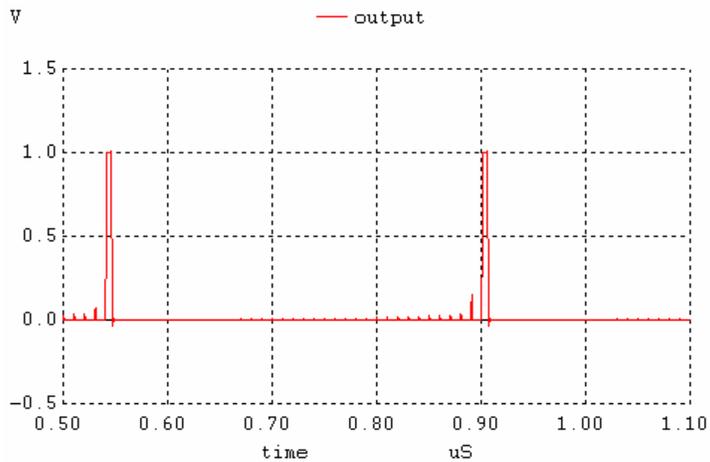


Figure 2.

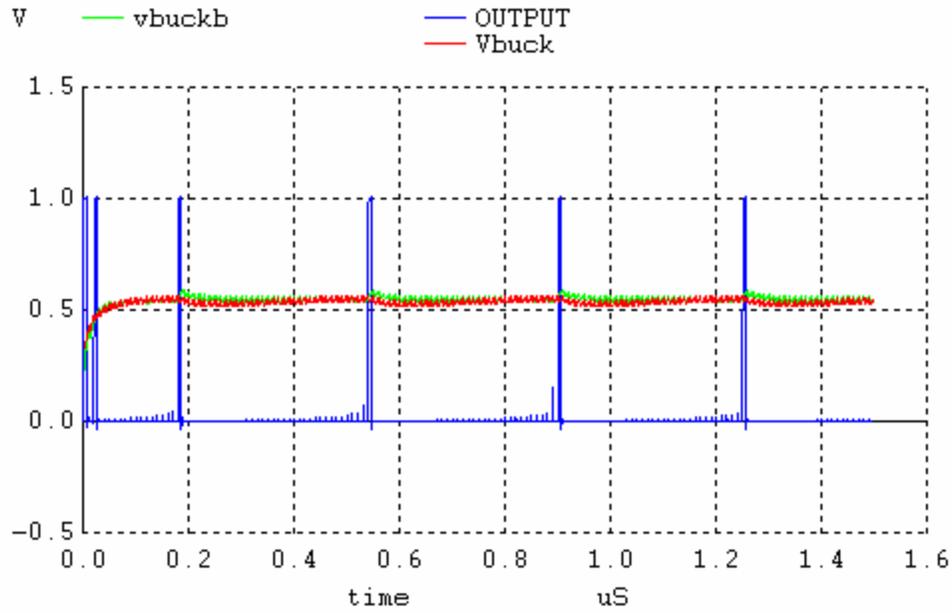


Figure 17.37a.

The simulation results for figure 17.37a, above show it's comparator making full logic levels, this is because of the SR latch on the outputs it's comparator.

Comparing figures 17.37a through e with figures 17.44a through e, below, we see that:

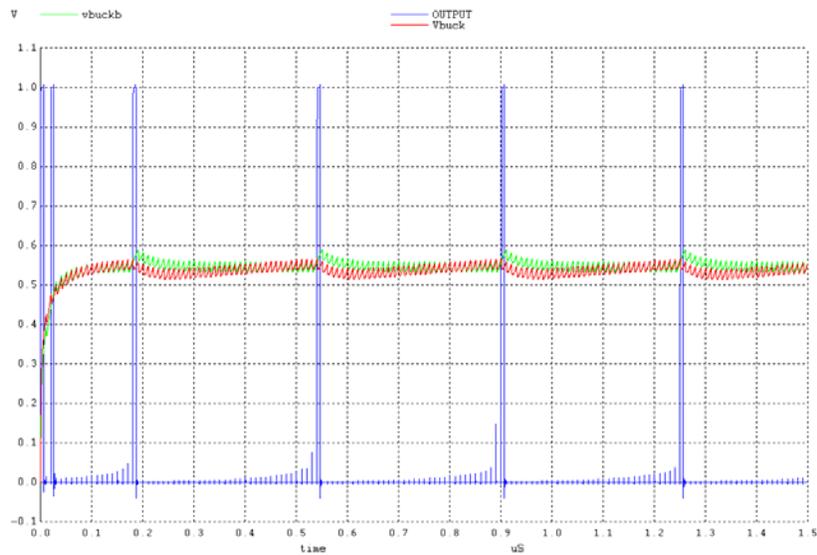


Figure 17.44a

$V_{Ishift} = 640\text{mV} - 215\text{mV} = 425\text{mV}$, and the sensed value is $435\text{mV} * 94/100 = 418\text{mV}$. This is compared to 426mV sensed in figure 17.37a.

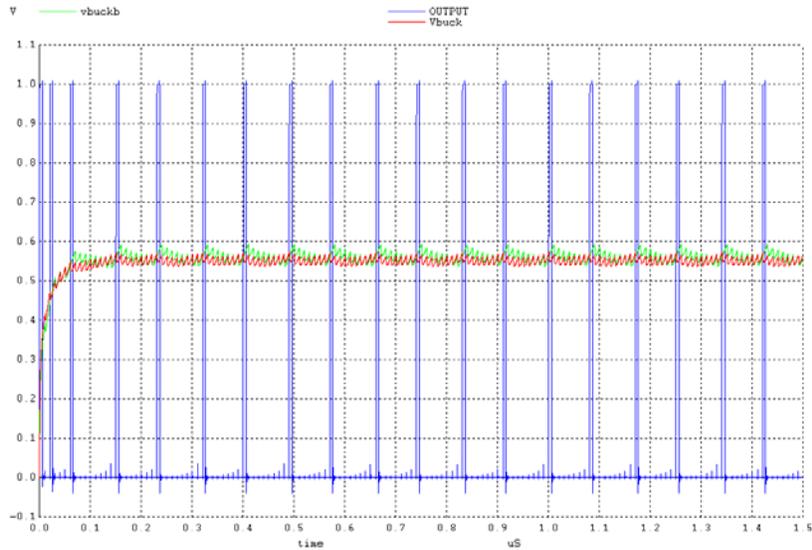


Figure 17.44b

$V_{shift} = 600\text{mV} - 215\text{mV} = 385\text{mV}$, and the sensed value is $435\text{mV} \cdot 89/100 = 387\text{mV}$.
 Compared to 382mV in figure 17.37b.

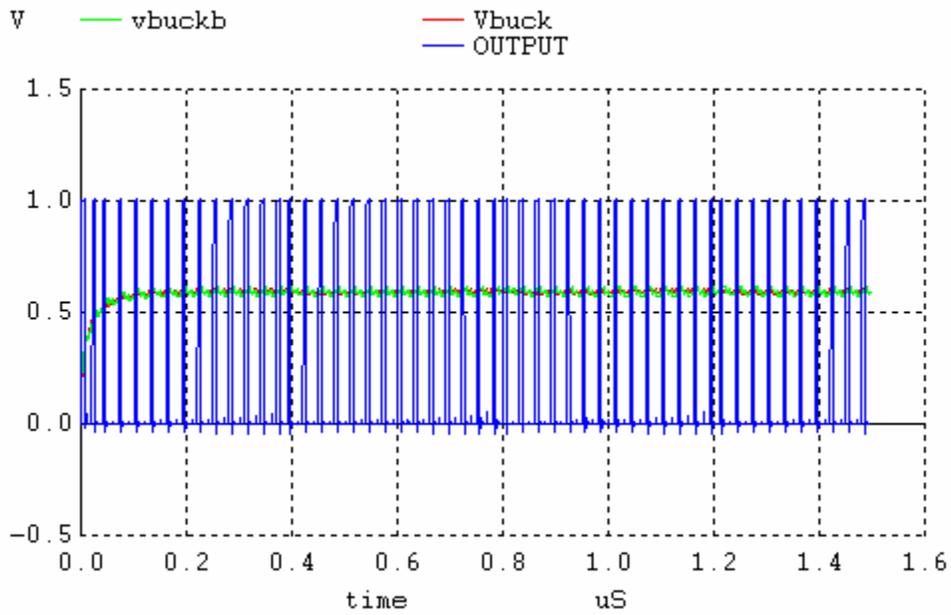


Figure 17.44c

$V_{shift} = 500\text{mV} - 215\text{mV} = 285\text{mV}$, and the sensed value is $435\text{mV} \cdot 66/100 = 287\text{mV}$. Compared with 283mV .

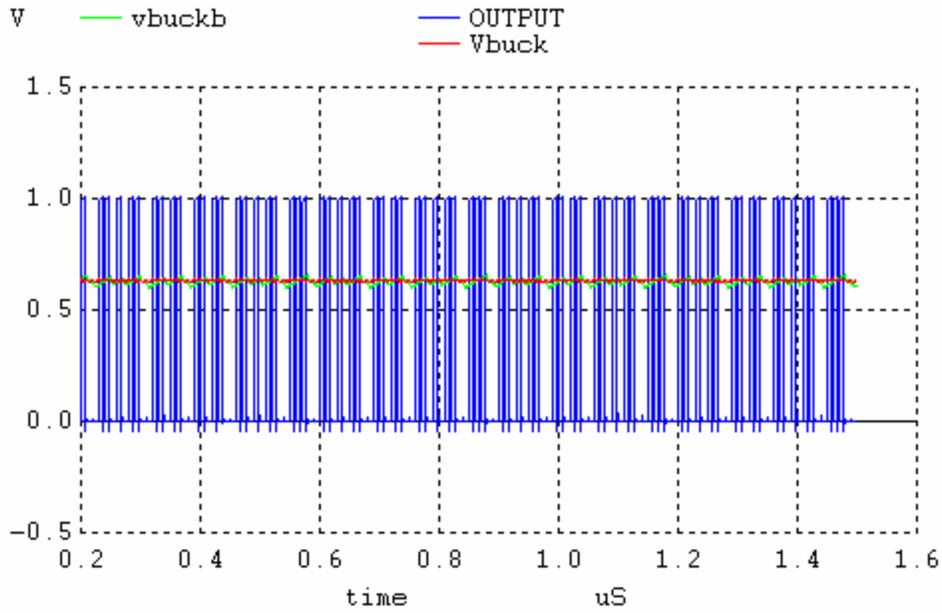


Figure 17.44d

$V_{\text{shift}} = 400\text{mV} - 215\text{mV} = 185\text{mV}$, and the sensed value is $435\text{mV} \cdot 44/100 = 191\text{mV}$. This is compared to a value of 191mV in figure 17.37d.

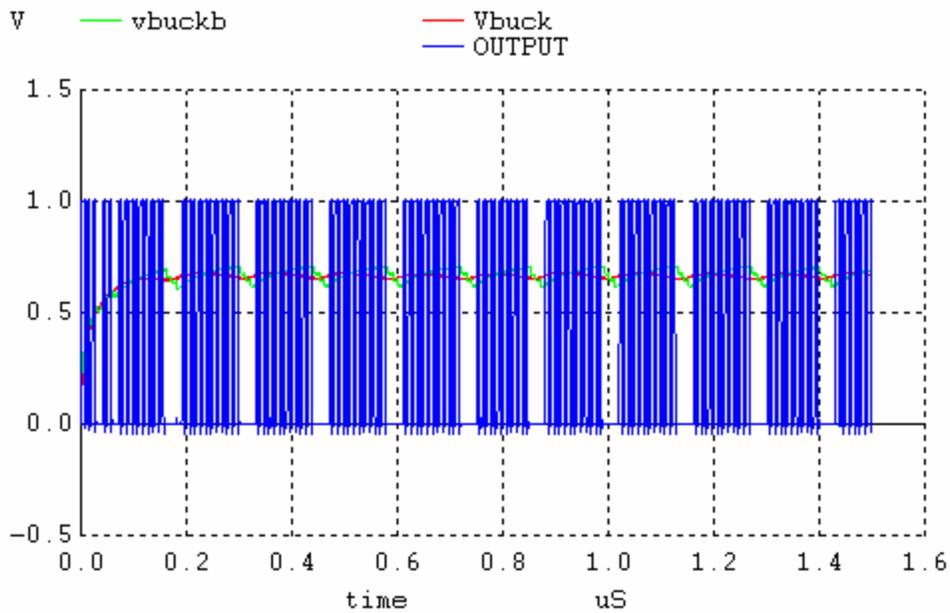


Figure 17.44e

$V_{\text{shift}} = 300\text{mV} - 215\text{mV} = 85\text{mV}$, and the sensed value is $435\text{mV} \cdot 22/100 = 96\text{mV}$. This is compared to a value of 104 mV.

As can be seen from the figures above, the fact that the comparator doesn't make full logic levels, indicates that our resolution will be off.

```
.control
destroy all
run
plot Vbuck vbuckb OUTPUT
.endc
```

```
.option scale=50n
.tran .25n 1500n 0 .25n UIC
```

```
VDD      VDD      0      DC      1
Vphi1    phi1    0      DC      0      PULSE 0 1 1n 0 0 4n 10n
Vphi2    phi2    0      DC      0      PULSE 0 1 6n 0 0 4n 10n
```

```
Vblack   Vr      0      DC      650mV
Vinten   Vi      0      DC      300mV
```

```
M1r      Vbuckb   vr      vdr2    0      NMOS L=1 W=10
M2r      Vdr2    OUTB    vdr3    0      NMOS L=1 W=10
M3r      Vdr3    phi1    vdr4    0      NMOS L=1 W=10
M4r      Vdr4    phi2    0        0      NMOS L=1 W=10
Mcupr    VDD      vdr4    VDD      VDD    PMOS L=10 W=50
```

```
M1i      Vbuck    vi      vdi2    0      NMOS L=1 W=10
M2i      Vdi2    VDD     vdi3    0      NMOS L=1 W=10
M3i      Vdi3    phi1    vdi4    0      NMOS L=1 W=10
M4i      Vdi4    phi2    0        0      NMOS L=1 W=10
Mcupi    VDD      Vdi4    VDD      VDD    PMOS L=10 W=50
```

```
M1p      vbuckb   vbuckb   VDD     VDD     PMOS L=10 W=10
M2p      vbuck    Vbuckb   VDD     VDD     PMOS L=10 W=10
Mbuck    0        Vbuck    0        0      NMOS L=10 W=500
Mbuckb   0        Vbuckb   0        0      NMOS L=10 W=500
```

```
MCP1     vp1      Vbuck    VDD     VDD     PMOS L=1 W=20
MCP2     vp2      out      vp1     VDD     PMOS L=1 W=20
MCP3     outb     phi2     vp2     VDD     PMOS L=1 W=20
MCP4     vp3      Vbuckb   VDD     VDD     PMOS L=1 W=20
MCP5     vp4      outb     vp3     VDD     PMOS L=1 W=20
MCP6     out      phi2     vp4     VDD     PMOS L=1 W=20
```

```
MCN1     outb     phi2     0        0      NMOS L=1 W=10
MCN2     outb     out      0        0      NMOS L=1 W=10
MCN3     out      outb     0        0      NMOS L=1 W=10
MCN4     out      phi2     0        0      NMOS L=1 W=10
```

```
MINV1    OUT1_   OUT      VDD     VDD     PMOS L=1 W=2
MINV2    OUT1_   OUT      0        0      NMOS L=1 W=4
MINV3    OUTPUT  OUT1_   VDD     VDD     PMOS L=1 W=2
MINV4    OUTPUT  OUT1_   0        0      NMOS L=1 W=4
```

* BSIM4 models